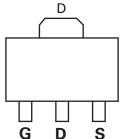


HALOGEN FREE

P-Channel 30-V (D-S) MOSFET

PRODU	(, b(, g				
V _{DS} (V)	$R_{DS(on)}\left(\Omega\right)$	I _D (A) ^d	Q _g (Typ.)		
- 30	0.050 at V _{GS} = - 10 V	- 7.6	13 nC		
- 30	0.056 at V _{GS} = - 4.5 V	- 6.0	13110		

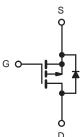


FEATURES

- Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET[®] Power MOSFET
- 100 % R_g Tested

APPLICATIONS

- Load Switch
- Battery Switch



P-Channel MOSFET

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	- 30	V	
Gate-Source Voltage	V _{GS}	± 20	V	
	T _C = 25 °C		- 7.6	
Continuous Drain Current (T _{.1} = 150 °C)	T _C = 70 °C	1 , [- 5.8	
Continuous Diain Curient (1) = 150 °C)	T _A = 25 °C	l _D	- 6.0 ^{a, b}	
	T _A = 70 °C		- 5.2 ^{a, b}	Α
Pulsed Drain Current	I _{DM}	- 35		
Ossilianos Ossilia Districtorio	T _C = 25 °C		- 3.5	
Continuous Source-Drain Diode Current	T _A = 25 °C	l _s	- 2.1 ^{a, b}	
	T _C = 25 °C		6.5	
	T _C = 70 °C		3.5	147
Maximum Power Dissipation	T _A = 25 °C	P _D	2.5 ^{a, b}	– w
	T _A = 70 °C		1.6 ^{a, b}	
Operating Junction and Storage Temperature Rang	T _J , T _{stq}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS							
Parameter	Symbol	Typical	Maximum	Unit			
Maximum Junction-to-Ambient ^{a, c}	t ≤ 10 s	R _{thJA}	40	50	°C/W		
Maximum Junction-to-Foot	Steady State	R _{thJF}	24	30	C/VV		

Notes

- a. Surface mounted on 1" x 1" FR4 board.
- b. t = 10 s.
- c. Maximum under Steady State conditions is 95 °C/W.
- d. Package limited.

S P



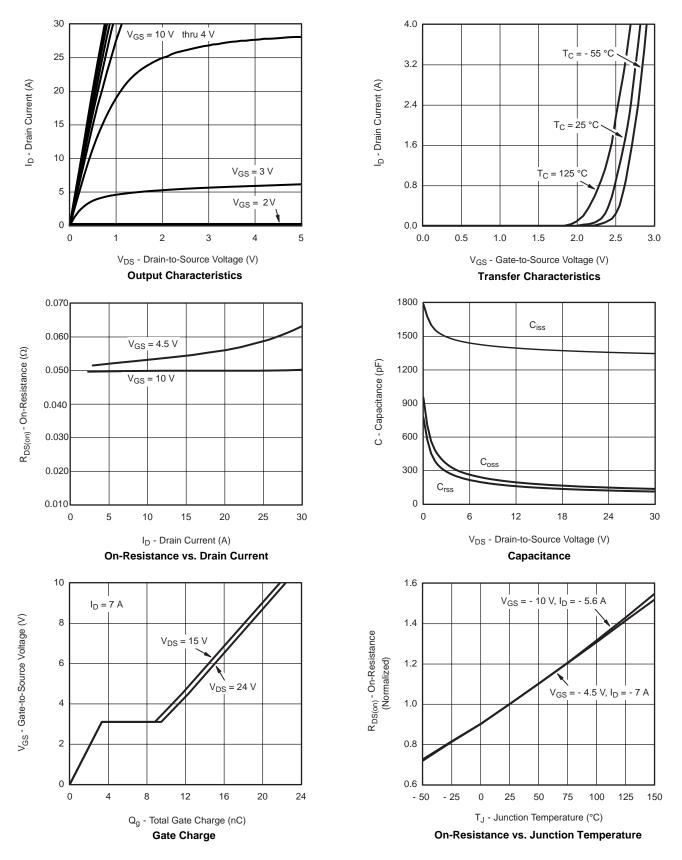
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 30			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = - 250 μA		- 31		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	η = - 250 μΑ		4.5		
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 1.0		- 2.5	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zara Cata Valtaga Drain Current	I	V _{DS} = - 30 V, V _{GS} = 0 V			- 1	μΑ
Zero Gate Voltage Drain Current	IDSS	V _{DS} = - 30 V, V _{GS} = 0 V, T _J = 55 °C			- 5	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \le -5 \text{ V}, V_{GS} = -10 \text{ V}$	- 20			Α
	D	V _{GS} = - 10 V, I _D = - 7.0 A		0.050		Ω
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = - 4.5 V, I _D = - 5.6 A		0.056		
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 15 V, I _D = - 7.0 A		18		S
Dynamic ^b		·				
Input Capacitance	C _{iss}			1355		
Output Capacitance	C _{oss}			180		pF
Reverse Transfer Capacitance	C _{rss}			145		1 '
Tatal Cata Obarra	Q _g	$V_{DS} = -15 \text{ V}, V_{GS} = -10 \text{ V}, I_{D} = -7.0 \text{ A}$		25	38	nC
Total Gate Charge				13	20	
Gate-Source Charge	Q_{gs}	$V_{DS} = -15 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -7.0 \text{ A}$		3.5		
Gate-Drain Charge	Q _{qd}			5.5		
Gate Resistance	R _g f = 1 MHz		0.4	2.0	4.0	Ω
Turn-On Delay Time	t _{d(on)}			10	20	
Rise Time	t _r	$V_{DD} = -15 \text{ V}, R_{L} = 2.7 \Omega$		13	20	
Turn-Off DelayTime	t _{d(off)}	$I_D \cong -5.6 \text{ A}, V_{GEN} = -10 \text{ V}, R_g = 1 \Omega$		23	35	
Fall Time	t _f			9	18	1
Turn-On Delay Time	t _{d(on)}			38	57	ns
Rise Time	t _r	$V_{DD} = -15 \text{ V}, R_{L} = 2.7 \Omega$		89	134	1
Turn-Off DelayTime	t _{d(off)}	$I_{D} \cong -5.6 \text{ A}, V_{GEN} = -4.5 \text{ V}, R_{g} = 1 \Omega$		22	33	1
Fall Time	t _f			11	17	1
Drain-Source Body Diode Characteris	tics					
Continous Source-Drain Diode Current I _S Pulse Diode Forward Current I _{SM}		T _C = 25 °C			- 6.5	A
					- 30	
Body Diode Voltage	V _{SD}	I _S = - 5.6 A, V _{GS} = 0 V		- 0.71	- 1.2	V
Body Diode Reverse Recovery Time	t _{rr}			22	33	ns
Body Diode Reverse Recovery Charge	Q _{rr}	1		17	26	nC
Reverse Recovery Fall Time	t _a	$I_F = -5.6 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 °\text{C}$		13		ns
Reverse Recovery Rise Time	t _b	1		9		

Notes:

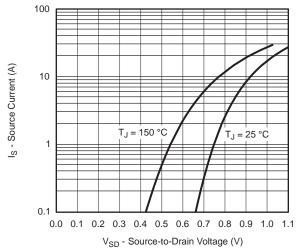
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

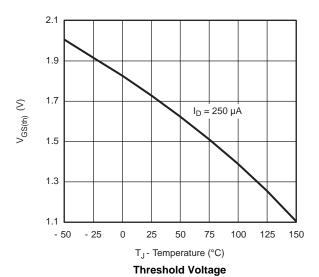






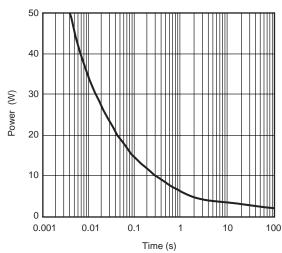


Source-Drain Diode Forward Voltage

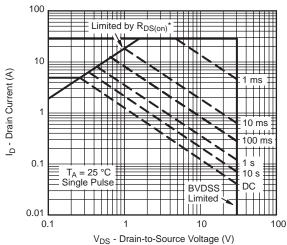


0.05 $I_D = 7 A$ 0.04 $R_{DS(on)}$ - On-Resistance (Ω) T_J = 125 °C 0.03 0.02 T_J = 25 °C 0.01 0.00 0 12 16 20

 V_{GS} - Gate-to-Source Voltage (V) On-Resistance vs. Gate-to-Source Voltage



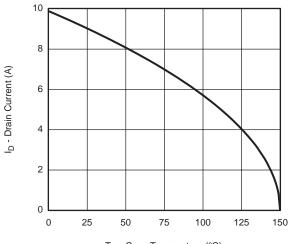
Single Pulse Power, Junction-to-Ambient



* V_{GS} > minimum V_{GS} at which $R_{DS(on)}$ is specified

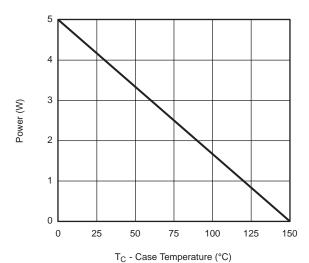
Safe Operating Area



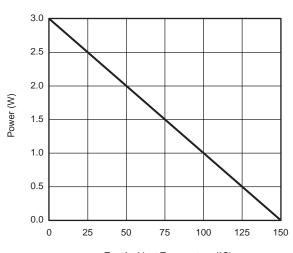


T_C - Case Temperature (°C)

Current Derating*



Power, Junction-to-Foot

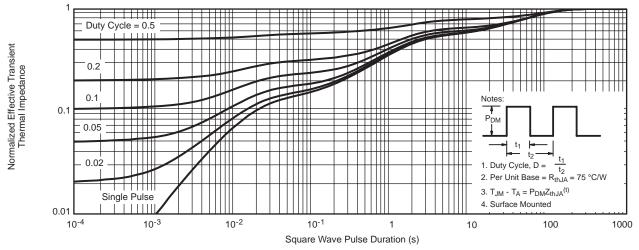


T_A - Ambient Temperature (°C)

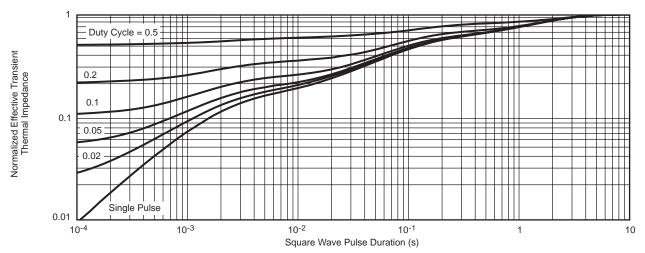
Power Derating, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





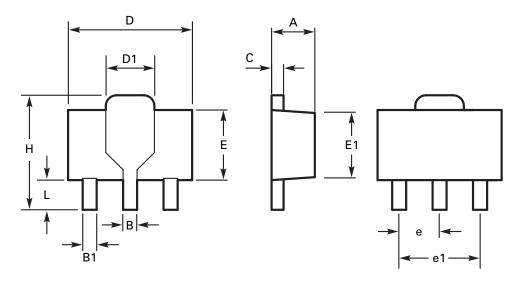
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot



Package outline - SOT89



DIM	Millin	neters	Inc	hes	DIM	Millimeters		Inches	
	Min	Max	Min	Max		Min	Max	Min	Max
Α	1.40	1.60	0.550	0.630	Е	2.29	2.60	0.090	0.102
В	0.44	0.56	0.017	0.022	E1	2.13	2.29	0.084	0.090
B1	0.36	0.48	0.014	0.019	е	1.50 BSC		0.059 BSC	
С	0.35	0.44	0.014	0.017	e1	3.00 BSC		0.118 BSC	
D	4.40	4.60	0.173	0.181	Н	3.94	4.25	0.155	0.167
D1	1.62	1.83	0.064	0.072	L	0.89	1.20	0.035	0.047

Note: Controlling dimensions are in millimeters. Approximate dimensions are provided in inches

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7



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